

POSITIONS AVAILABLE

SEM Technicians & Operators

Applied Magnetics Corporation has immediate openings for SEM Technicians and SEM Operators to staff shifts for an around-the-clock manufacturing operation. Emphasis will be on critical dimension measurements using field emission SEM instruments at low accelerating voltage. Equipment specific training is available. Technicians will be responsible for instrument maintenance, operator training, and instrument operation. Operators will perform critical dimension measurements and routine analyses. Technicians and operators will work closely with staff engineers and manufacturing personnel.

A minimum of one year direct SEM experience is preferred. The successful candidates will have good communication skills, the ability to perform with minimal supervision, and excellent organizational abilities.

Applied Magnetics offers a competitive compensation and benefits package. Qualified candidates will receive immediate consideration by sending or faxing their resume to:

A Applied Magnetics Corporation
6300 Hollister Avenue • Goleta, CA 93117
FAX (805) 683-3018
WE ARE AN EQUAL OPPORTUNITY EMPLOYER

- ✓ Mechanical engineers, metallurgists, chemists, physical scientists and technical experts in industry, universities and government with experience in evaluating the performance of materials are needed by NIST to conduct on-site assessments of laboratories that perform testing and inspection of metals and fasteners. The assessors are required for a new National Voluntary Laboratory Accreditation Program to meet the requirements of the Fastener Quality Act of 1990. NVLAP will accredit laboratories to test and inspect metals and fasteners using techniques in mechanical and physical testing, chemical analysis, dimensional inspection, metallographic analysis, and non-destructive inspection. Individuals with a background in the testing and inspection of metals and fasteners, and with experience in laboratory management and operation, are invited to send a resume to S. Wayne Stiefel, Fastener Program Manager, NVLAP, Rm. A162, Bldg. 411, NIST, Gaithersburg, MD. 20899-0001, (301)975-4016, Fax: (301)926-2884.

USED EQUIPMENT FOR SALE

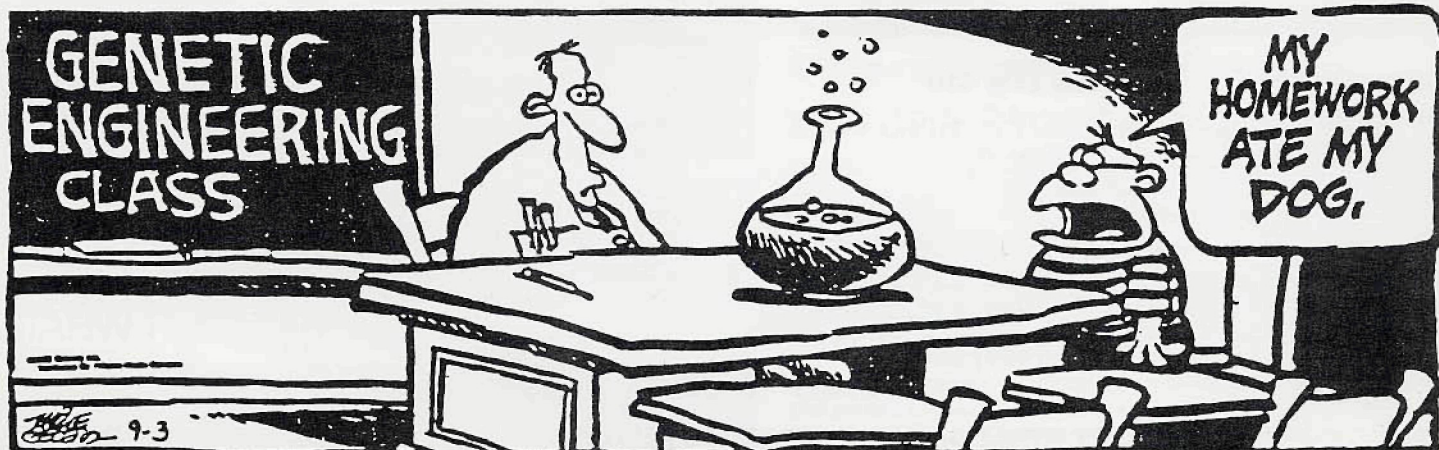
- ✓ **AMRAY 1400 Scanning Electron Microscope and Microscope Wavelength Spectrometer.** Kept under service contract during life. Kevin Selkregg, Carborundum Co.: (716)278-3850.
- ✓ **Jeol JSM 35CF SEM with optional Tracor 2000 EDX and imaging system.** Under service contract since new in 1981. Asking \$20,000 for package or \$15,000 for SEM only. Robert Keyse, Cornell Univ.: (607)255-6421
- ✓ **Jeol JEM-100CV/SEG TEM, 11 year old, in good operating condition.** Includes 1) specimen anticontamination trap; 2) goniometer state; 3) SEGZ-4D Zoom Stigmator; 4) Haskris water recirculator. Best offer. Call B. Soronson, Univ. of Maryland: (410)328-3855.
- ✓ **Balzers 360M Freeze-Fracture Apparatus.** A classic in good working order. \$5,000. Caroline Schooley, U.C. Berkeley: (510)642-2085.
- ✓ **FREE TEMs!!!**
Jeol JSEM-200 TEM/STEM with SE Goniometer and Jeol JEM-200A with TE Goniometer (in storage, perhaps best for spare parts for other). Many additional spares: set of good H.T. diodes; another JSEM-200 mostly complete except for vacuum system; compatible parts from an early JEM-200; column and electronics (including H.T. cables and components). Michael Marko, Wadsworth Labs.: (518)474-7049.

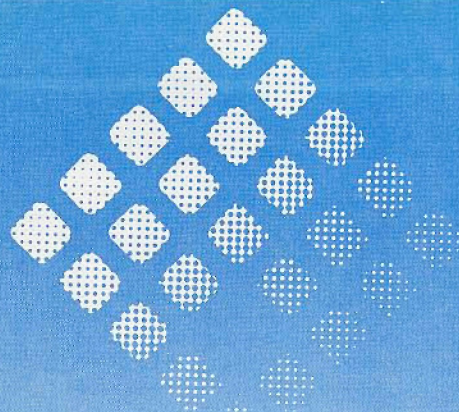
USED EQUIPMENT WANTED

- ✓ **CR2000 cryo attachment for RMC/DUPONT ultramicrotomes.** Call Dr. Mark W. Rigler, MAS Inc.: (800)421-8451.

A reminder that the improved MSAIEMSA BBS system is up and operational. You have only to:

- ★ *Connect your modem (1200-2400 baud, 8 data & 1 stop bit, no parity).*
- ★ *Telephone in toll-free: (800)627-3672.*
- ★ *Log in and establish your username and password.*





MATERIALS ANALYTICAL SERVICES

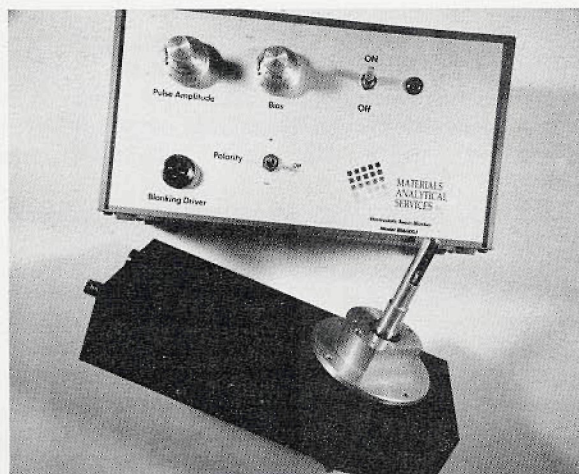
Materials Characterization for Today's Industry.

TECHNICAL
BULLETIN
550

ELECTROSTATIC BEAM BLANKER

MAS announces the availability of an Electrostatic Beam Blanker designed specifically for the JEOL 6400F Field Emission SEM. This system provides a switching speed of $<15\text{nsec}$ with leakage of $<10^{-4}$ x Beam Current. Although the Blanker was designed specifically for the 6400F, it is compatible with all 6400 series JEOL SEMs.

MAS is committed to the development of innovative instrumentation for advanced industrial and research micro-analysis applications.



MAS Model #BB6000J

MANUFACTURED AT MAS

Electrostatic Beam Blanker for JEOL 6400 series SEMs, Scanning Tunneling Microscopy probes (CG Pt/Ir Tips) and Atomic Force Microscopy Probes (HART™ Probes).

ROUTINE APPLICATIONS FOR THE ELECTROSTATIC BEAM BLANKER

- Lithography
- EDS Enhancement
- Cathodoluminescence
- Time Resolved EBIC
- Voltage Contrast

MATERIALS ANALYTICAL SERVICES

*Providing specialized components
for Electron Microscopy and
Scanning Probe Microscopy.*

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FT-IR
GC
XRF
XRD**
MICROANALYSIS LAB
FAILURE ANALYSIS
MICROSTRUCTURE
PARTICLE CHARACTERIZATION
SEMICONDUCTORS
FOCUSED ION BEAM
FIBERS
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POLYMERS

1-800-421-8451

3597 Parkway Lane • Suite 250 • Norcross, Georgia 30092 • 404-448-3200 • FAX 404-368-8256 or
2418 Blue Ridge Road • Suite 105 • Raleigh, North Carolina 27607 • 919-881-7708 • FAX 919-881-8227

